

CD4011A, CD4012A, CD4023A Types

CMOS NAND Gates

- Quad 2 Input – CD4011A
- Dual 4 Input – CD4012A
- Triple 3 Input – CD4023A

The TI-CD4011A, CD4012A, and CD-4023A NAND gates provide the system designer with direct implementation of the NAND function and supplement the existing family of CMOS gates.

These types are supplied in 14-lead hermetic dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), 14-lead ceramic flat packages (K suffix), and in chip form (H suffix).

Features:

- Quiescent current specified to 15 V
- Maximum input leakage of 1 μ A at 15 V (full package-temperature range)
- 1-V noise margin (full package-temperature range)

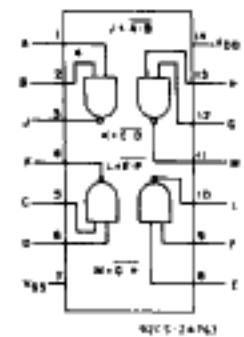
RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

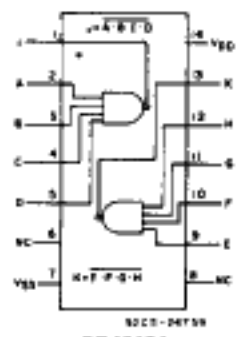
Characteristic	Min.	Max.	Units
Supply Voltage Range (over full package temperature range)	3	12	V

MAXIMUM RATINGS, Absolute-Maximum Values:

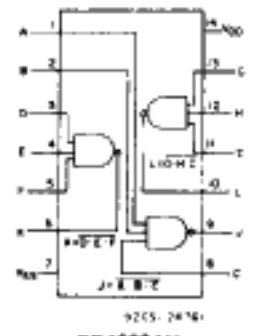
STORAGE-TEMPERATURE RANGE (T_{STG})	–85 to +150°C
OPERATING-TEMPERATURE RANGE (T_A)	
PACKAGE TYPES D, F, K, H	–55 to +125°C
PACKAGE TYPE E	–40 to +85°C
DC SUPPLY-VOLTAGE RANGE, (V_{DD})	
(Voltages referenced to V_{SS} Terminal)	–0.5 to +15 V
POWER DISSIPATION PER PACKAGE (P_{Dh})	
FOR $T_A = -40$ to +60°C (PACKAGE TYPE E)	500 mW
FOR $T_A = +60$ to +85°C (PACKAGE TYPE E)	Derate Linearly at 12 mW/°C to 200 mW
FOR $T_A = -55$ to +100°C (PACKAGE TYPES D, F, K)	500 mW
FOR $T_A = +100$ to +125°C (PACKAGE TYPES D, F, K)	Derate Linearly at 12 mW/°C to 200 mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR $T_A =$ FULL PACKAGE-TEMPERATURE RANGE (ALL PACKAGE TYPES)	100 mW
INPUT VOLTAGE RANGE, ALL INPUTS	–0.5 to $V_{DD} + 0.5$ V
LEAD TEMPERATURE (DURING SOLDERING):	
At distance 1/16 \pm 1/32 inch (1.59 \pm 0.79 mm) from case for 10 s max	+265°C



CD4011A

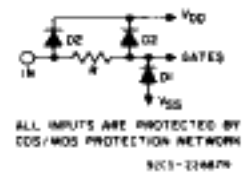


CD4012A



CD4023AH

Fig. 1 – Functional diagrams.



SC11-224679

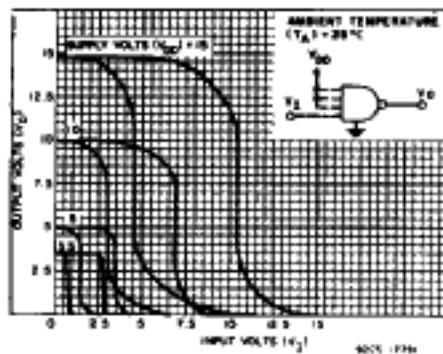


Fig. 2 – Minimum & maximum voltage transfer characteristics.

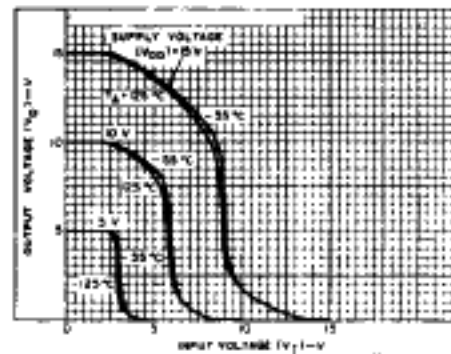


Fig. 3 – Typical voltage transfer characteristics as a function of temperature.

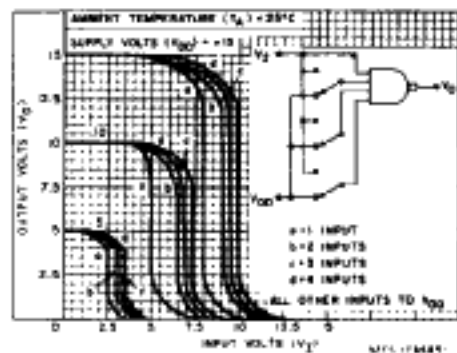


Fig. 4 – Typical multiple input switching transfer characteristics for CD4012A.

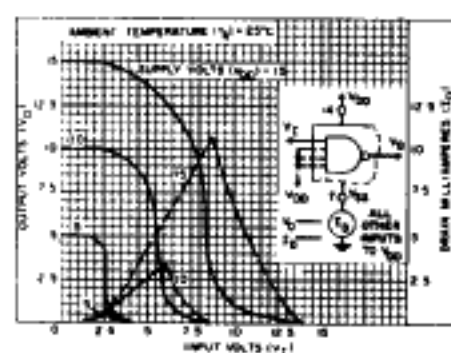


Fig. 5 – Typical current & voltage transfer characteristics.

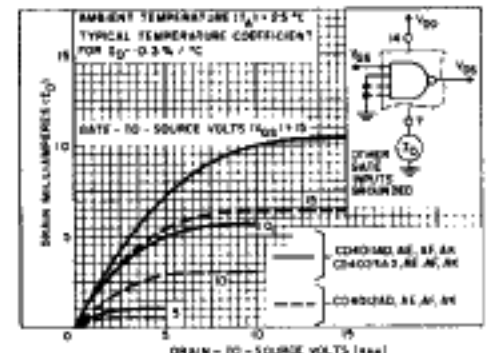


Fig. 6 – Typical n-channel drain characteristics.

CD4011A, CD4012A, CD4023A Types

STATIC ELECTRICAL CHARACTERISTICS

Characteristic	Conditions			Limits at Indicated Temperatures (°C)								Units
	V _O (V)	V _{IN} (V)	V _{DD} (V)	D, F, K, H Packages				E Package				
				-55	+25		+125	-40	+25		+85	
				Typ.	Limit			Typ.	Limit			
Quiescent Device Current, I _L Max.	-	-	5	0.05	0.001	0.05	3	0.5	0.005	0.5	15	μA
	-	-	10	0.1	0.001	0.1	6	5	0.005	5	30	
	-	-	15	2	0.02	2	40	50	0.5	50	500	
Output Voltage: Low-Level V _{OL}	-	0.5	5	0 Typ.; 0.05 Max.								V
	-	0.10	10	0 Typ.; 0.05 Max.								
High Level, V _{OH}	-	0.5	5	4.95 Min.; 5 Typ.								V
	-	0.10	10	8.95 Min.; 10 Typ.								
Noise Immunity: Inputs Low, V _{NL}	3.6	-	5	1.5 Min.; 2.25 Typ.								V
	7.2	-	10	3 Min.; 4.5 Typ.								
Inputs High, V _{NH}	1.4	-	5	1.5 Min.; 2.25 Typ.								V
	2.8	-	10	3 Min.; 4.5 Typ.								
Noise Margin: Inputs Low, V _{NML}	4.5	-	5	1 Min.								V
	9	-	10	1 Min.								
Inputs High, V _{NMH}	0.5	-	5	1 Min.								
	1	-	10	1 Min.								
Output Drive Current: N-Channel (Sink) I _{DN} Min.												mA
CD4011A	0.5	-	5	0.31	0.5	0.25	0.175	0.145	0.5	0.12	0.095	
CD4023A	0.5	-	10	0.62	0.6	0.5	0.35	0.3	0.6	0.25	0.2	
CD4012A	0.5	-	5	0.15	0.25	0.12	0.085	0.072	0.25	0.06	0.05	
	0.5	-	10	0.31	0.6	0.25	0.175	0.155	0.6	0.13	0.105	
P-Channel (Source), I _{DP} Min. All Types	4.5	-	5	-0.31	-0.5	-0.25	-0.175	-0.145	-0.5	-0.12	-0.095	
	9.5	-	10	-0.75	-1.2	-0.6	-0.4	-0.36	-1.2	-0.3	-0.24	
Input Leakage Current, I _{IL} , I _{IH}	Any Input		15	±10 ⁻⁵ Typ.; ±1 Max.								μA

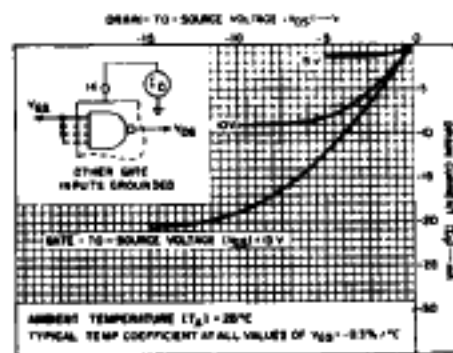


Fig. 7 - Typical p-channel drain characteristics.

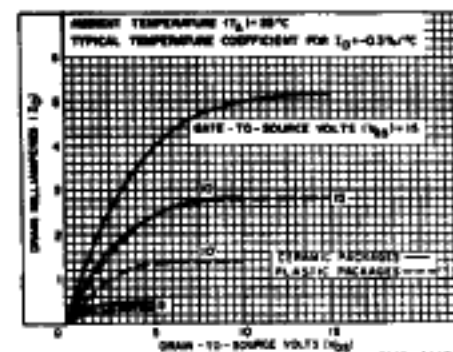


Fig. 8 - Minimum n-channel drain characteristics - CD4011A & CD4023A.

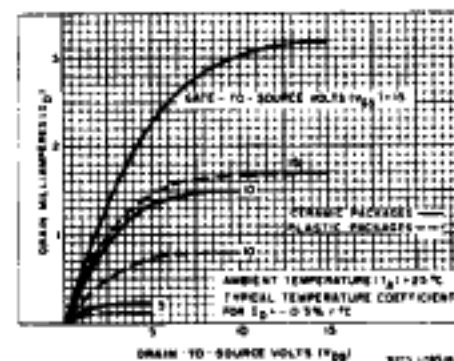


Fig. 9 - Minimum n-channel drain characteristics.

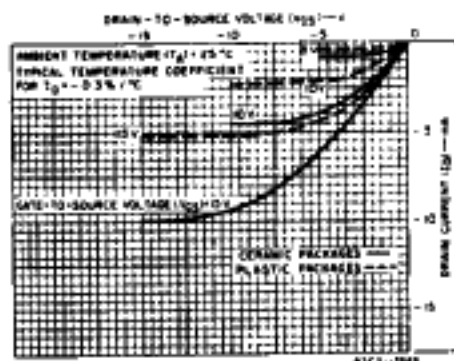


Fig. 10 - Minimum p-channel drain characteristics.

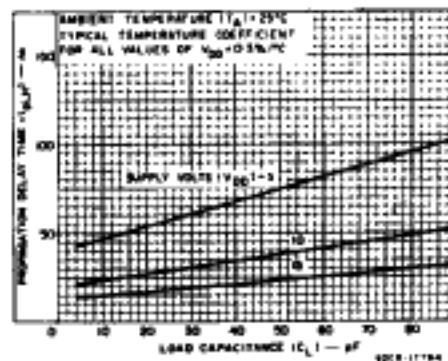


Fig. 11 - Typical low-to-high level propagation delay time vs. C_L.

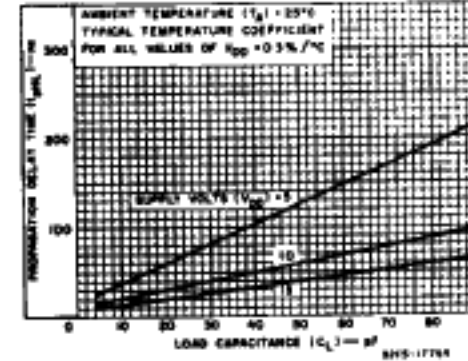


Fig. 12 - Typical high-to-low level propagation delay time vs. C_L - CD4011A, & CD4023A.

CD4011A, CD4012A, CD4023A Types

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^\circ\text{C}$, $C_L = 15\text{ pF}$, Input $t_r, t_f = 20\text{ ns}$, $R_L = 200\text{ k}\Omega$

CHARACTERISTICS	TEST CONDITIONS	LIMITS				UNITS	
		D, F, K, H Packages		E Package			
		V _{DD} (V)	Typ.	Max.	Typ.		Max.
Propagation Delay Time: Low-to-High Level, t_{PLH}		5	50	75	50	100	ns
		10	25	40	25	50	
High-to-Low Level, t_{PHL} CD4011A and CD4023A		5	50	75	50	100	ns
		10	25	40	25	50	
CD4012A		5	100	150	100	200	ns
		10	50	75	50	100	
Transition Time: Low-to-High Level, t_{TLH}		5	75	100	75	125	ns
		10	40	60	40	75	
High-to-Low Level, t_{THL} CD4011A and CD4023A		5	75	125	75	150	ns
		10	50	75	50	100	
CD4012A		5	250	375	250	500	ns
		10	125	200	125	250	
Input Capacitance, C_i	Any Input	5	—	5	—	—	pF

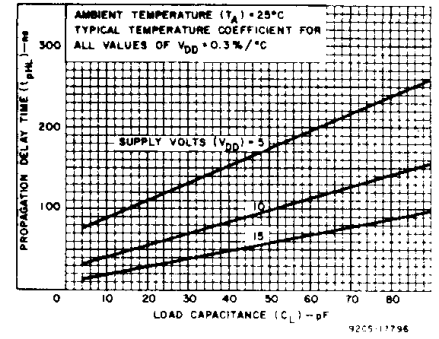


Fig. 13 — Typical high-to-low level propagation delay time vs. C_L — CD4012A.

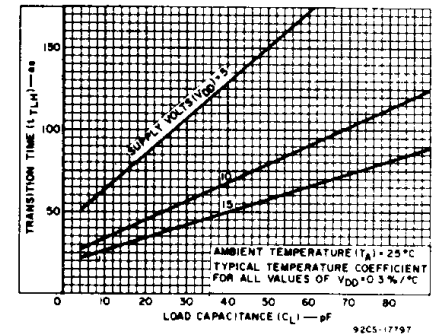


Fig. 14 — Typical low-to-high transition time vs. C_L .

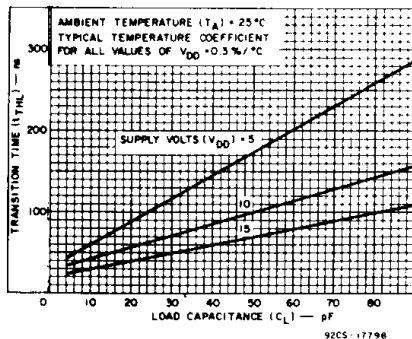


Fig. 15 — Typical high-to-low level transition time vs. C_L — CD4011A & CD4023A.

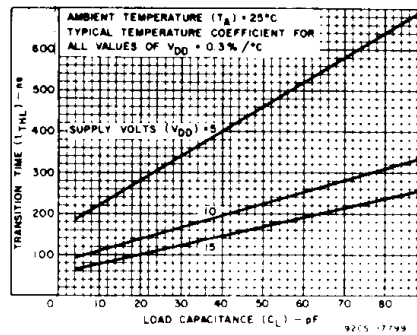


Fig. 16 — Typical high-to-low level transition time vs. C_L — CD4012A.

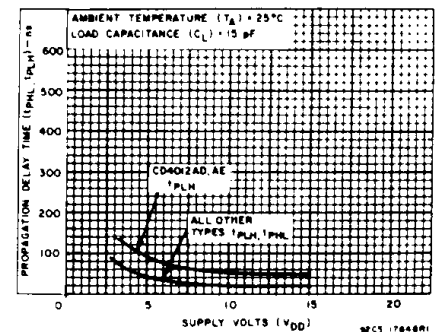


Fig. 17 — Minimum propagation delay time vs. V_{DD} .

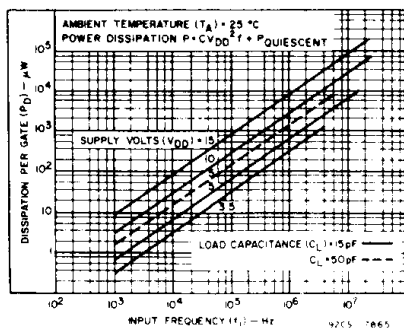


Fig. 18 — Typical dissipation characteristics.

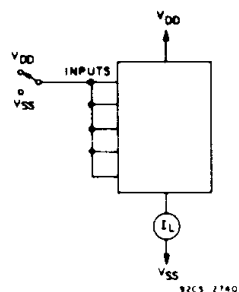


Fig. 19 — Quiescent device current test circuit.

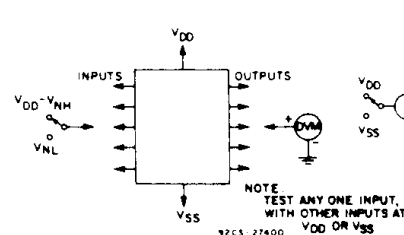


Fig. 20 — Noise immunity test circuit.

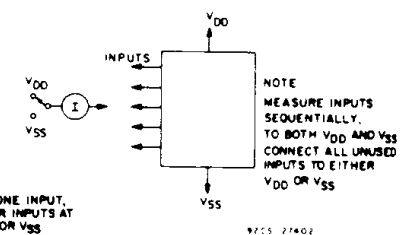


Fig. 21 — Input leakage current test circuit.

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Mailing Address:

Texas Instruments
Post Office Box 655303
Dallas, Texas 75265